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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Not For New Designs
Core Processor	ARM® Cortex® -M0+
Core Size	32-Bit Single-Core
Speed	50MHz
Connectivity	I ² C, SPI, UART/USART
Peripherals	DMA, LCD, WDT
Number of I/O	38
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 3.6V
Data Converters	A/D 6x16b, 4x24b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mkm33z128clh5r

1 Ordering parts

1.1 Determining valid order-able parts

Valid order-able part numbers are provided on the web. To determine the order-able part numbers for this device, go to freescale.com and perform a part number search for the following device numbers:

- MKM13Z64CHH5
- MKM14Z64CHH5
- MKM14Z128CHH5
- MKM32Z64CLH5
- MKM33Z64CLH5
- MKM33Z128CLH5
- MKM32Z64CLL5
- MKM33Z64CLL5
- MKM33Z128CLL5
- MKM34Z128CLL5
- MKM38Z128CLL5

2 Part identification

2.1 Description

Part numbers for the chip have fields that identify the specific part. You can use the values of these fields to determine the specific part you have received.

2.2 Format

Part numbers for this device have the following format:

Q K M S R FFF T PP CC N

2.3 Fields

Following table lists the possible values for each field in the part number (not all combinations are valid):

Field	Description	Values
Q	Qualification status	<ul style="list-style-type: none"> M = Fully qualified, general market flow P = Pre-qualification (Proto)
K	Main family	<ul style="list-style-type: none"> K = Kinetis
M	Sub family	<ul style="list-style-type: none"> M1 = Metering only (No LCD support) M3 = Metering with LCD support
S	Number of Sigma Delta (SD) ADC	<ul style="list-style-type: none"> 2 = 1 SD ADC with PGA and 1 SD ADC 3 = 2 SD ADC with PGA and 1 SD ADC 4 = 2 SD ADC with PGA and 2 SD ADC 8 = Same as '4'.
R	Silicon revision	<ul style="list-style-type: none"> Z = Initial (Blank) = Main A = Revision after main
FFF	Program flash memory size	<ul style="list-style-type: none"> 64 = 64 KB 128 = 128 KB
T	Temperature range (°C)	<ul style="list-style-type: none"> C = -40 to 85
PP	Package identifier	<ul style="list-style-type: none"> HH = 44 LGA (5 mm x 5 mm) LH = 64 LQFP (10 mm x 10 mm) LL = 100 LQFP (14 mm x 14 mm)
CC	Maximum CPU frequency (MHz)	<ul style="list-style-type: none"> 5 = 50 MHz
N	Packaging type	<ul style="list-style-type: none"> R = Tape and reel (Blank) = Trays

2.4 Example

This is an example part number:

- MKM34Z128CLL5

3 Terminology and guidelines

3.1 Definition: Operating requirement

An *operating requirement* is a specified value or range of values for a technical characteristic that you must guarantee during operation to avoid incorrect operation and possibly decreasing the useful life of the chip.

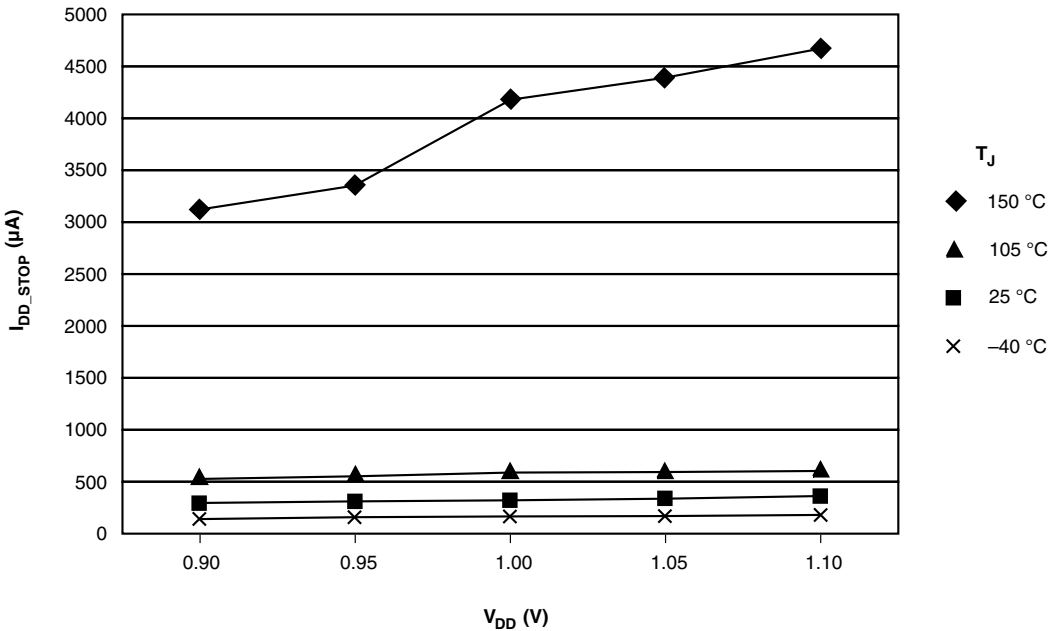
3.8.1 Example 1

This is an example of an operating behavior that includes a typical value:

Symbol	Description	Min.	Typ.	Max.	Unit
I_{WP}	Digital I/O weak pullup/pulldown current	10	70	130	μA

3.8.2 Example 2

This is an example of a chart that shows typical values for various voltage and temperature conditions:



3.9 Typical value conditions

Typical values assume you meet the following conditions (or other conditions as specified):

Symbol	Description	Value	Unit
T_A	Ambient temperature	25	$^{\circ}C$
V_{DD}	3.3 V supply voltage	3.3	V

4 Ratings

4.1 Thermal handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
T _{STG}	Storage temperature	-55	150	°C	1
T _{SDR}	Solder temperature, lead-free	—	260	°C	2

1. Determined according to JEDEC Standard JESD22-A103, *High Temperature Storage Life*.
2. Determined according to IPC/JEDEC Standard J-STD-020, *Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices*.

4.2 Moisture handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
MSL	Moisture sensitivity level	—	3	—	1

1. Determined according to IPC/JEDEC Standard J-STD-020, *Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices*.

4.3 ESD handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
V _{HBM}	Electrostatic discharge voltage, human body model (All pins except RESET pin)	-4000	+4000	V	1
	Electrostatic discharge voltage, human body model (RESET pin only)	-2500	+2500	V	1
V _{CDM}	Electrostatic discharge voltage, charged-device model (for corner pins)	-750	+750	V	2
V _{CDM}	Electrostatic discharge voltage, charged-device model	-500	+500	V	3
V _{PESD}	Powered ESD voltage	-6000	+6000	V	
I _{LAT}	Latch-up current at ambient temperature of 105°C	-100	+100	mA	

1. Determined according to JEDEC Standard JESD22-A114, *Electrostatic Discharge (ESD) Sensitivity Testing Human Body Model (HBM)*.
2. Determined according to JEDEC Standard JESD22-C101, *Field-Induced Charged-Device Model Test Method for Electrostatic-Discharge-Withstand Thresholds of Microelectronic Components*.
3. Determined according to JEDEC Standard JESD22-C101, *Field-Induced Charged-Device Model Test Method for Electrostatic-Discharge-Withstand Thresholds of Microelectronic Components*.

4.4 Voltage and current operating ratings

Symbol	Description	Min.	Max.	Unit
V_{DD}	Digital supply voltage	-0.3	3.6	V
V_{DIO}	Digital input voltage (except RESET, EXTAL, and XTAL)	-0.3	$V_{DD} + 0.3$	V
$V_{DTamper}$	Tamper input voltage	-0.3	$V_{BAT} + 0.3$	V
V_{AIO}	Analog ¹ , RESET, EXTAL, and XTAL input voltage	-0.3	$V_{DD} + 0.3$	V
I_D	Instantaneous maximum current single pin limit (applies to all port pins)	-25	25	mA
V_{DDA}	Analog supply voltage	$V_{DD} - 0.3$	$V_{DD} + 0.3$	V
V_{BAT}	RTC battery supply voltage	-0.3	3.6	V

1. Analog pins are defined as pins that do not have an associated general purpose I/O port function.

5 General

5.1 AC electrical characteristics

Unless otherwise specified, propagation delays are measured from the 50% to the 50% point, and rise and fall times are measured at the 20% and 80% points, as shown in the following figure.

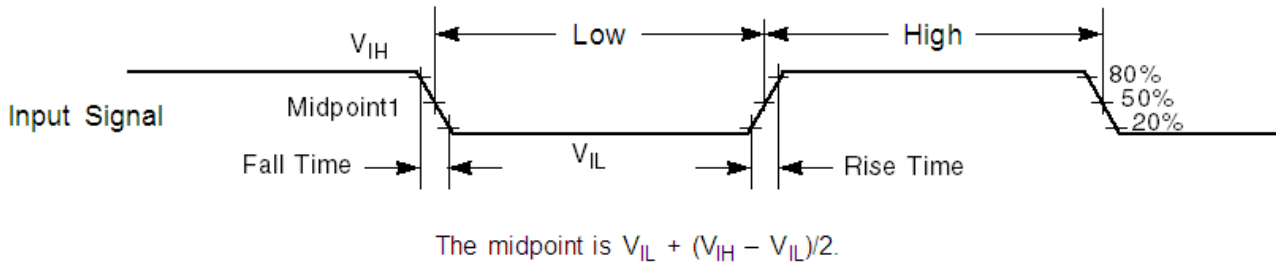


Figure 1. Input signal measurement reference

5.2 Nonswitching electrical specifications

5.2.1 Voltage and current operating requirements

Table 1. Voltage and current operating requirements

Symbol	Description	Min.	Max.	Unit	Notes
V_{DD}	Supply voltage when AFE is operational	2.7	3.6	V	
	Supply voltage when AFE is NOT operational	1.71	3.6	V	
V_{DDA}	Analog supply voltage	2.7	3.6	V	
$V_{DD} - V_{DDA}$	V_{DD} -to- V_{DDA} differential voltage	-0.1	0.1	V	
$V_{SS} - V_{SSA}$	V_{SS} -to- V_{SSA} differential voltage	-0.1	0.1	V	
V_{BAT}	RTC battery supply voltage	1.71	3.6	V	1
V_{IH}	Input high voltage <ul style="list-style-type: none"> $2.7\text{ V} \leq V_{DD} \leq 3.6\text{ V}$ $1.7\text{ V} \leq V_{DD} \leq 2.7\text{ V}$ 	$0.7 \times V_{DD}$	—	V	
		$0.75 \times V_{DD}$	—	V	
V_{IL}	Input low voltage <ul style="list-style-type: none"> $2.7\text{ V} \leq V_{DD} \leq 3.6\text{ V}$ $1.7\text{ V} \leq V_{DD} \leq 2.7\text{ V}$ 	—	$0.35 \times V_{DD}$	V	
		—	$0.3 \times V_{DD}$	V	
V_{HYS}	Input hysteresis	$0.06 \times V_{DD}$	—	V	
I_{ICDIO}	Digital pin negative DC injection current — single pin <ul style="list-style-type: none"> $V_{IN} < V_{SS}-0.3\text{V}$ 	-5	—	mA	
I_{ICAIO}	Analog ² , EXTAL, and XTAL pin DC injection current — single pin <ul style="list-style-type: none"> $V_{IN} < V_{SS}-0.3\text{V}$ (Negative current injection) $V_{IN} > V_{DD}+0.3\text{V}$ (Positive current injection) 	-3	—	mA	
		—	+3		
I_{ICcont}	Contiguous pin DC injection current —regional limit, includes sum of negative injection currents or sum of positive injection currents of 16 contiguous pins <ul style="list-style-type: none"> Negative current injection Positive current injection 	-25	—	mA	
		—	+25		
V_{RFVBAT}	V_{BAT} voltage required to retain the VBAT register file	V_{POR_VBAT}	—	V	

- V_{BAT} always needs to be there for the chip to be operational.
- Analog pins are defined as pins that do not have an associated general purpose I/O port function.

5.2.2 LVD and POR operating requirements

Table 2. V_{DD} supply LVD and POR operating requirements

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V_{POR}	Falling VDD POR detect voltage	0.8	1.1	1.5	V	
V_{LVDH}	Falling low-voltage detect threshold — high range (LVDV=01)	2.48	2.56	2.64	V	

Table continues on the next page...

Table 4. Voltage and current operating behaviors (continued)

Symbol	Description	Min.	Max.	Unit	Notes
V_{OL}	Output low voltage — high-drive strength				
	• $2.7\text{ V} \leq V_{DD} \leq 3.6\text{ V}$, $I_{OL} = 20\text{ mA}$	—	0.5	V	
	• $1.71\text{ V} \leq V_{DD} \leq 2.7\text{ V}$, $I_{OL} = 10\text{ mA}$	—	0.5	V	
	Output low voltage — low-drive strength				
	• $2.7\text{ V} \leq V_{DD} \leq 3.6\text{ V}$, $I_{OL} = 5\text{ mA}$	—	0.5	V	
	• $1.71\text{ V} \leq V_{DD} \leq 2.7\text{ V}$, $I_{OL} = 2.5\text{ mA}$	—	0.5	V	
I_{OLT}	Output low current total for all ports	—	100	mA	
I_{OZ}	Hi-Z (off-state) leakage current (per pin)	—	1	μA	
R_{PU}	Internal pullup resistors	30	60	$k\Omega$	1,
R_{PD}	Internal pulldown resistors	30	60	$k\Omega$	2

1. Measured at $V_{input} = V_{SS}$

2. Measured at $V_{input} = V_{DD}$

5.2.4 Power mode transition operating behaviors

All specifications except t_{POR} , and $VLLSx \rightarrow \text{RUN}$ recovery times in the following table assume this clock configuration:

- CPU and system clocks = 50 MHz
- Bus clock = 25 MHz
- Flash clock = 25 MHz
- Temp: $-40\text{ }^{\circ}\text{C}$, $25\text{ }^{\circ}\text{C}$, and $85\text{ }^{\circ}\text{C}$
- V_{DD} : 1.71 V, 3.3 V, and 3.6 V

Table 5. Power mode transition operating behaviors

Symbol	Description	Min.	Max.	Unit	Notes
t_{POR}	After a POR event, amount of time from the point V_{DD} reaches 1.71 V to execute the first instruction across the operating temperature range of the chip.	563	659	μs	1
	• $VLLS0 \rightarrow \text{RUN}$	—	372	μs	
	• $VLLS1 \rightarrow \text{RUN}$	—	372	μs	
	• $VLLS2 \rightarrow \text{RUN}$	—	273	μs	
	• $VLLS3 \rightarrow \text{RUN}$	—	273	μs	
	• $VLPS \rightarrow \text{RUN}$	—	5.0	μs	

Table continues on the next page...

Table 6. Power consumption operating behaviors (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
I_{DD_VLPW}	Very-low-power wait mode current at 3.0 V — all peripheral clocks disabled <ul style="list-style-type: none"> • 25 °C • -40 °C • 105 °C 	—	162	350	μA	6
		—	158.50	330	μA	
		—	446.94	1700	μA	
		—	—	—	—	
I_{DD_STOP}	Stop mode current at 3.0 V <ul style="list-style-type: none"> • 25 °C • -40 °C • 105 °C 	—	311.90	730	μA	
		—	364	700	μA	
		—	645.13	2250	μA	
		—	—	—	—	
I_{DD_VLPS}	Very-low-power stop mode current at 3.0 V <ul style="list-style-type: none"> • 25 °C • -40 °C • 105 °C 	—	8.56	46	μA	
		—	—	44	μA	
		—	—	1500	μA	
		—	—	—	—	
I_{DD_VLLS3}	Very low-leakage stop mode 3 current at 3.0 V <ul style="list-style-type: none"> • 25 °C • -40 °C • 105 °C 	—	1.98	3.5	μA	
		—	—	3.3	μA	
		—	—	85	μA	
		—	—	—	—	
I_{DD_VLLS2}	Very low-leakage stop mode 2 current at 3.0 V <ul style="list-style-type: none"> • 25 °C • -40 °C • 105 °C 	—	1.24	2.6	μA	
		—	—	2.5	μA	
		—	—	59.5	μA	
		—	—	—	—	
I_{DD_VLLS1}	Very low-leakage stop mode 1 current at 3.0 V <ul style="list-style-type: none"> • 25 °C • -40 °C • 105 °C 	—	0.89	1.7	μA	
		—	—	1.6	μA	
		—	—	38.8	μA	
		—	—	—	—	
I_{DD_VLLS0}	Very low-leakage stop mode 0 current at 3.0 V with POR detect circuit disabled <ul style="list-style-type: none"> • 25 °C • -40 °C • 105 °C 	—	0.35	0.67	μA	
		—	—	0.64	μA	
		—	—	38	μA	
		—	—	—	—	
I_{DD_VLLS0}	Very low-leakage stop mode 0 current at 3.0 V with POR detect circuit enabled <ul style="list-style-type: none"> • 25 °C • -40 °C • 105 °C 	—	0.472	0.76	μA	
		—	—	0.72	μA	
		—	—	38.4	μA	
		—	—	—	—	
I_{DD_VBAT}	Average current with RTC and 32 kHz disabled at 3.0 V and VDD is OFF <ul style="list-style-type: none"> • 25 °C • -40 °C • 105 °C 	—	0.3	1	μA	
		—	—	0.95	μA	
		—	—	15	μA	
		—	—	—	—	

Table continues on the next page...

5.2.7 Designing with radiated emissions in mind

To find application notes that provide guidance on designing your system to minimize interference from radiated emissions:

1. Go to www.freescale.com.
2. Perform a keyword search for “EMC design.”

5.2.8 Capacitance attributes

Table 8. Capacitance attributes

Symbol	Description	Min.	Max.	Unit
C_{IN_A}	Input capacitance: analog pins	—	7	pF
C_{IN_D}	Input capacitance: digital pins	—	7	pF
$C_{IN_D_io60}$	Input capacitance: fast digital pins	—	9	pF

5.3 Switching specifications

5.3.1 Device clock specifications

Table 9. Device clock specifications

Symbol	Description	Min.	Max.	Unit	Notes
Normal run mode					
f_{SYS}	System and core clock		50	MHz	
f_{BUS}	Bus clock		25	MHz	
f_{FLASH}	Flash clock		25	MHz	
f_{AFE}	AFE Modulator clock		6.5	MHz	
VLPR mode ¹					
f_{SYS}	System and core clock		2	MHz	
f_{BUS}	Bus clock		1	MHz	
f_{FLASH}	Flash clock		1	MHz	
f_{AFE}	AFE Modulator clock ²		1.6	MHz	

1. The frequency limitations in VLPR mode here override any frequency specification listed in the timing specification for any other module.
2. AFE working in low-power mode.

Table 18. MCG specifications (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
f_{VCO}	VCO operating frequency	11.71875	12.288	14.6484375	MHz	
I_{PLL}	PLL operating current <ul style="list-style-type: none"> IO 3.3 V current Max core voltage current 	—	300 100	—	μA	9
f_{PLL_ref}	PLL reference frequency range	31.25	32.768	39.0625	kHz	
J_{cyc_pll}	PLL period jitter (RMS) <ul style="list-style-type: none"> $f_{VCO} = 12$ MHz 			700	ps	10
D_{lock}	Lock entry frequency tolerance	± 1.49	—	± 2.98	%	11
D_{unl}	Lock exit frequency tolerance	± 4.47	—	± 5.97	%	
t_{pll_lock}	Lock detector detection time	—	—	$150 \times 10^{-6} + 1075(1/f_{pll_ref})$	s	12

1. This parameter is measured with the internal reference (slow clock) being used as a reference to the FLL (FEI clock mode).
2. These typical values listed are with the slow internal reference clock (FEI) using factory trim and DMX32=0.
3. Chip max freq is 50 MHz, so Mid-range with DRS = 10 and High-range of DCO cannot be used and should not be configured.
4. These typical values listed are with the slow internal reference clock (FEI) using factory trim and DMX32=1.
5. The resulting clock frequency must not exceed the maximum specified clock frequency of the device.
6. Chip max freq is 50 MHz, so Mid-range with DRS = 10 and High-range of DCO cannot be used and should not be configured.
7. This specification is based on standard deviation (RMS) of period or frequency.
8. This specification applies to any time the FLL reference source or reference divider is changed, trim value is changed, DMX32 bit is changed, DRS bits are changed, or changing from FLL disabled (BLPE, BLPI) to FLL enabled (FEI, FEE, FBE, FBI). If a crystal/resonator is being used as the reference, this specification assumes it is already running.
9. Excludes any oscillator currents that are also consuming power while PLL is in operation.
10. This specification was obtained using a Freescale developed PCB. PLL jitter is dependent on the noise characteristics of each PCB and results will vary.
11. Will be updated later
12. This specification applies to any time the PLL VCO divider or reference divider is changed, or changing from PLL disabled (BLPE, BLPI) to PLL enabled (PBE, PEE). If a crystal/resonator is being used as the reference, this specification assumes it is already running.

6.2.2 Oscillator electrical specifications

6.2.2.1 Oscillator DC electrical specifications

Table 19. Oscillator DC electrical specifications

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V_{DD}	Supply voltage	1.71	—	3.6	V	

Table continues on the next page...

Table 19. Oscillator DC electrical specifications (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
I _{DDOSC}	Supply current — low-power mode (HGO=0)					1
	• 32 kHz	—	500	—	nA	
	• 1 MHz	—	200	—	μA	
	• 4 MHz	—	200	—	μA	
	• 8 MHz (RANGE=01)	—	300	—	μA	
	• 16 MHz	—	950	—	μA	
	• 24 MHz	—	1.2	—	mA	
	• 32 MHz	—	1.5	—	mA	
I _{DDOSC}	Supply current — high-gain mode (HGO=1)					1
	• 32 kHz	—	25	—	μA	
	• 1 MHz	—	300	—	μA	
	• 4 MHz	—	400	—	μA	
	• 8 MHz (RANGE=01)	—	500	—	μA	
	• 16 MHz	—	2.5	—	mA	
	• 24 MHz	—	3	—	mA	
	• 32 MHz	—	4	—	mA	
C _x	EXTAL load capacitance	—	—	—		2, 3
C _y	XTAL load capacitance	—	—	—		2, 3
	Capacitance of EXTAL	247	—	—	ff	
	• Die level (100 LQFP) • Package level (100 LQFP)	0.495			pF	
	Capacitance of XTAL	265	—	—	ff	
	• Die level (100 LQFP) • Package level (100 LQFP)	0.495			pF	
R _F	Feedback resistor — low-frequency, low-power mode (HGO=0)	—	—	—	MΩ	2, 4
	Feedback resistor — low-frequency, high-gain mode (HGO=1)	—	10	—	MΩ	
	Feedback resistor — high-frequency, low-power mode (HGO=0)	—	—	—	MΩ	
	Feedback resistor — high-frequency, high-gain mode (HGO=1)	—	1	—	MΩ	

Table continues on the next page...

6.4.1.1 16-bit ADC operating conditions

Table 27. 16-bit ADC operating conditions

Symbol	Description	Conditions	Min.	Typ. ¹	Max.	Unit	Notes
V_{DDA}	Supply voltage	Absolute	1.71	—	3.6	V	
ΔV_{DDA}	Supply voltage	Delta to V_{DD} ($V_{DD} - V_{DDA}$)	-100	0	+100	mV	2
ΔV_{SSA}	Ground voltage	Delta to V_{SS} ($V_{SS} - V_{SSA}$)	-100	0	+100	mV	2
V_{REFH}	ADC reference voltage high		1.13	V_{DDA}	V_{DDA}	V	
V_{REFL}	ADC reference voltage low		V_{SSA}	V_{SSA}	V_{SSA}	V	
V_{ADIN}	Input voltage		V_{REFL}	—	V_{REFH}	V	
C_{ADIN}	Input capacitance	<ul style="list-style-type: none"> 16-bit mode 8-bit / 10-bit / 12-bit modes 	—	8	10	pF	
R_{ADIN}	Input series resistance		—	2	5	k Ω	
R_{AS}	Analog source resistance (external)	12-bit modes $f_{ADCK} < 4$ MHz	—	—	5	k Ω	3
f_{ADCK}	ADC conversion clock frequency	\leq 12-bit mode	1.0	—	18.0	MHz	4
f_{ADCK}	ADC conversion clock frequency	16-bit mode	2.0	—	12.0	MHz	4
C_{rate}	ADC conversion rate	\leq 12-bit modes No ADC hardware averaging Continuous conversions enabled, subsequent conversion time	20.000	—	818.330	Ksps	5
C_{rate}	ADC conversion rate	16-bit mode No ADC hardware averaging Continuous conversions enabled, subsequent conversion time	37.037	—	461.467	Ksps	5

1. Typical values assume $V_{DDA} = 3.0$ V, Temp = 25 °C, $f_{ADCK} = 1.0$ MHz, unless otherwise stated. Typical values are for reference only, and are not tested in production.
2. DC potential difference.
3. This resistance is external to MCU. To achieve the best results, the analog source resistance must be kept as low as possible. The results in this data sheet were derived from a system that had $< 8 \Omega$ analog source resistance. The R_{AS}/C_{AS} time constant should be kept to < 1 ns.
4. To use the maximum ADC conversion clock frequency, CFG2[ADHSC] must be set and CFG1[ADLPC] must be clear.
5. For guidelines and examples of conversion rate calculation, download the [ADC calculator tool](#).

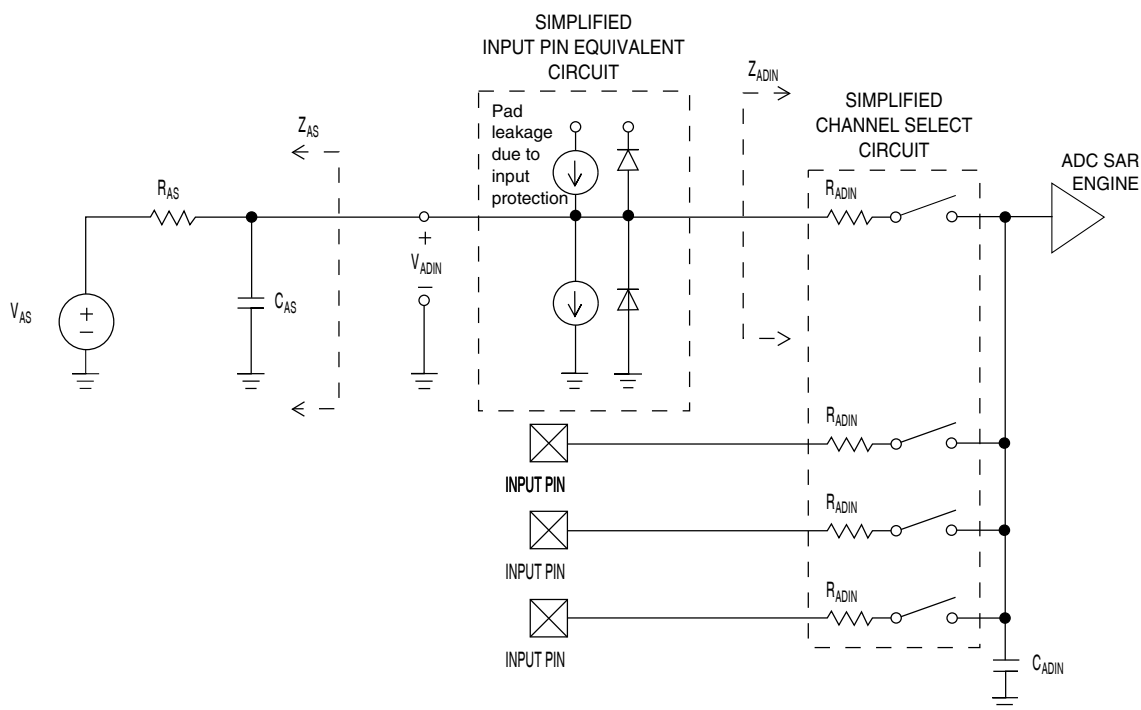


Figure 2. ADC input impedance equivalency diagram

6.4.1.2 16-bit ADC electrical characteristics

Table 28. 16-bit ADC characteristics ($V_{REFH} = V_{DDA}$, $V_{REFL} = V_{SSA}$)

Symbol	Description	Conditions ¹	Min.	Typ. ²	Max.	Unit	Notes
I_{DDA_ADC}	Supply current		0.215	—	1.7	mA	3
f_{ADACK}	ADC asynchronous clock source	<ul style="list-style-type: none"> ADLPC = 1, ADHSC = 0 ADLPC = 1, ADHSC = 1 ADLPC = 0, ADHSC = 0 ADLPC = 0, ADHSC = 1 	1.2 2.4 3.0 4.4	2.4 4.0 5.2 6.2	3.9 6.1 7.3 9.5	MHz MHz MHz MHz	$t_{ADACK} = 1/f_{ADACK}$
	Sample Time	See Reference Manual chapter for sample times					
TUE	Total unadjusted error	<ul style="list-style-type: none"> 12-bit modes <12-bit modes 	— —	±4 ±1.4	±6.8 ±2.1	LSB ⁴	5
DNL	Differential non-linearity	<ul style="list-style-type: none"> 12-bit modes <12-bit modes 	— —	±0.7 ±0.2	−1.1 to +1.9 −0.3 to 0.5	LSB ⁴	5
INL	Integral non-linearity	<ul style="list-style-type: none"> 12-bit modes <12-bit modes 	— —	±1.0 ±0.5	−2.7 to +1.9 −0.7 to +0.5	LSB ⁴	5

Table continues on the next page...

Table 28. 16-bit ADC characteristics ($V_{REFH} = V_{DDA}$, $V_{REFL} = V_{SSA}$) (continued)

Symbol	Description	Conditions ¹	Min.	Typ. ²	Max.	Unit	Notes
E_{FS}	Full-scale error	<ul style="list-style-type: none"> 12-bit modes <12-bit modes 	—	–4	–5.4	LSB ⁴	$V_{ADIN} = V_{DDA}$ ⁵
E_Q	Quantization error	<ul style="list-style-type: none"> 16-bit modes 12-bit modes 	—	–1 to 0	—	LSB ⁴	
$ENOB$	Effective number of bits	16-bit single-ended mode <ul style="list-style-type: none"> Avg = 32 Avg = 4 	12.8 11.9	14.5 13.8	— —	bits bits	6
$SINAD$	Signal-to-noise plus distortion	See ENOB	$6.02 \times ENOB + 1.76$			dB	
THD	Total harmonic distortion	16-bit single-ended mode <ul style="list-style-type: none"> Avg = 32 	—	–94	—	dB	7
			—	–85	—	dB	
$SFDR$	Spurious free dynamic range	16-bit single-ended mode <ul style="list-style-type: none"> Avg = 32 	82	95	—	dB	7
			78	90	—	dB	
E_{IL}	Input leakage error		$I_{in} \times R_{AS}$			mV	I_{in} = leakage current (refer to the MCU's voltage and current operating ratings)
	Temp sensor slope	Across the full temperature range of the device	1.55	1.62	1.69	mV/°C	8
V_{TEMP25}	Temp sensor voltage	25 °C	706	716	726	mV	8

1. All accuracy numbers assume the ADC is calibrated with $V_{REFH} = V_{DDA}$
2. Typical values assume $V_{DDA} = 3.0$ V, Temp = 25 °C, $f_{ADCK} = 2.0$ MHz unless otherwise stated. Typical values are for reference only and are not tested in production.
3. The ADC supply current depends on the ADC conversion clock speed, conversion rate and ADC_CFG1[ADLPC] (low power). For lowest power operation, ADC_CFG1[ADLPC] must be set, the ADC_CFG2[ADHSC] bit must be clear with 1 MHz ADC conversion clock speed.
4. $1 \text{ LSB} = (V_{REFH} - V_{REFL})/2^N$
5. ADC conversion clock < 16 MHz, Max hardware averaging (AVGE = %1, AVGS = %11)
6. Input data is 100 Hz sine wave. ADC conversion clock < 12 MHz.
7. Input data is 1 kHz sine wave. ADC conversion clock < 12 MHz.

8. ADC conversion clock < 3 MHz

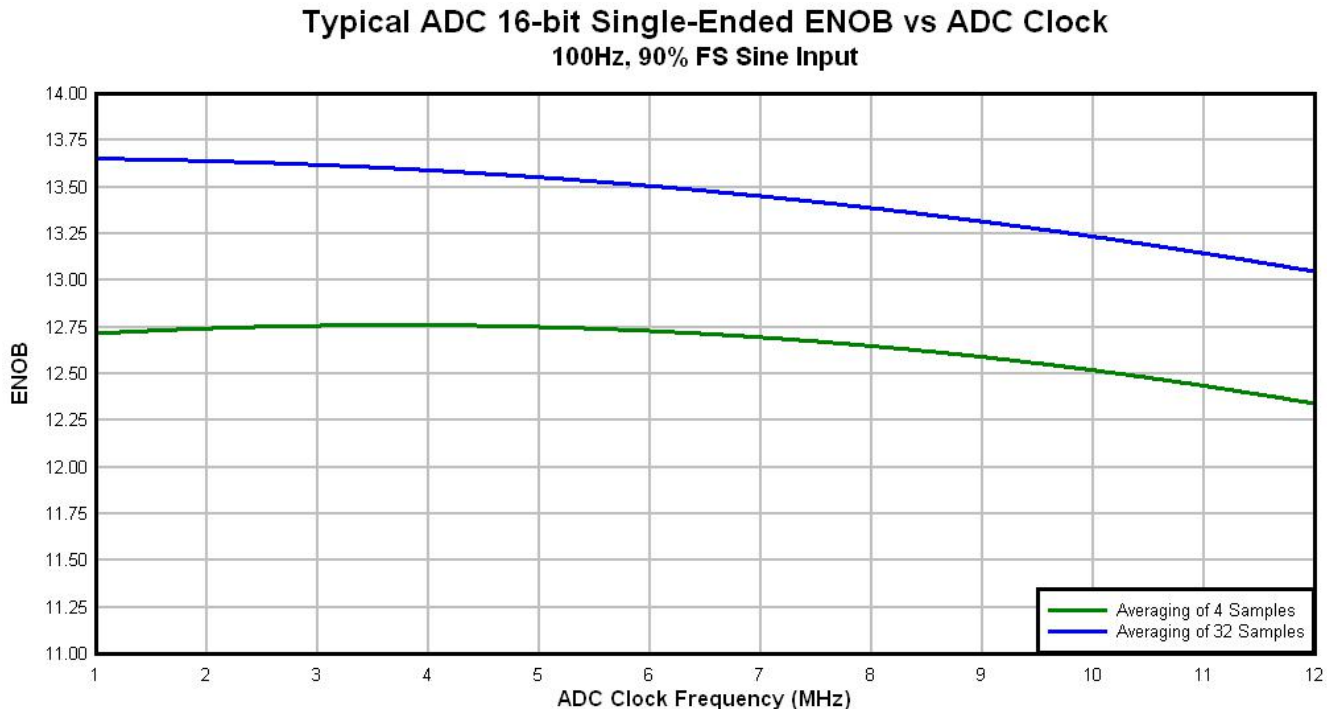


Figure 3. Typical ENOB vs. ADC_CLK for 16-bit single-ended mode

6.4.2 CMP and 6-bit DAC electrical specifications

Table 29. Comparator and 6-bit DAC electrical specifications

Symbol	Description	Min.	Typ.	Max.	Unit
V_{DD}	Supply voltage	1.71	—	3.6	V
I_{DDHS}	Supply current, High-speed mode (EN=1, PMODE=1)	—	—	200	μ A
$I_{DDL S}$	Supply current, low-speed mode (EN=1, PMODE=0)	—	—	20	μ A
V_{AIN}	Analog input voltage	$V_{SS} - 0.3$	—	V_{DD}	V
V_{AIO}	Analog input offset voltage	—	—	20	mV
V_H	Analog comparator hysteresis ¹ <ul style="list-style-type: none"> CR0[HYSTCTR] = 00 CR0[HYSTCTR] = 01 CR0[HYSTCTR] = 10 CR0[HYSTCTR] = 11 	—	5 10 20 30	—	mV mV mV mV
V_{CMPOh}	Output high	$V_{DD} - 0.5$	—	—	V
V_{CMPOl}	Output low	—	—	0.5	V
t_{DHS}	Propagation delay, high-speed mode (EN=1, PMODE=1)	20	50	200	ns

Table continues on the next page...

Table 29. Comparator and 6-bit DAC electrical specifications (continued)

Symbol	Description	Min.	Typ.	Max.	Unit
t_{DLS}	Propagation delay, low-speed mode (EN=1, PMODE=0)	80	250	600	ns
	Analog comparator initialization delay ²	—	—	40	μ s
I_{DAC6b}	6-bit DAC current adder (enabled)	—	7	—	μ A
INL	6-bit DAC integral non-linearity	-0.5	—	0.5	LSB ³
DNL	6-bit DAC differential non-linearity	-0.3	—	0.3	LSB

1. Typical hysteresis is measured with input voltage range limited to 0.6 to $V_{DD}-0.6$ V.
2. Comparator initialization delay is defined as the time between software writes to change control inputs (Writes to CMP_DACCR[DACEN], CMP_DACCR[VRSEL], CMP_DACCR[VOSEL], CMP_MUXCR[PSEL], and CMP_MUXCR[MSEL]) and the comparator output settling to a stable level.
3. 1 LSB = $V_{reference}/64$

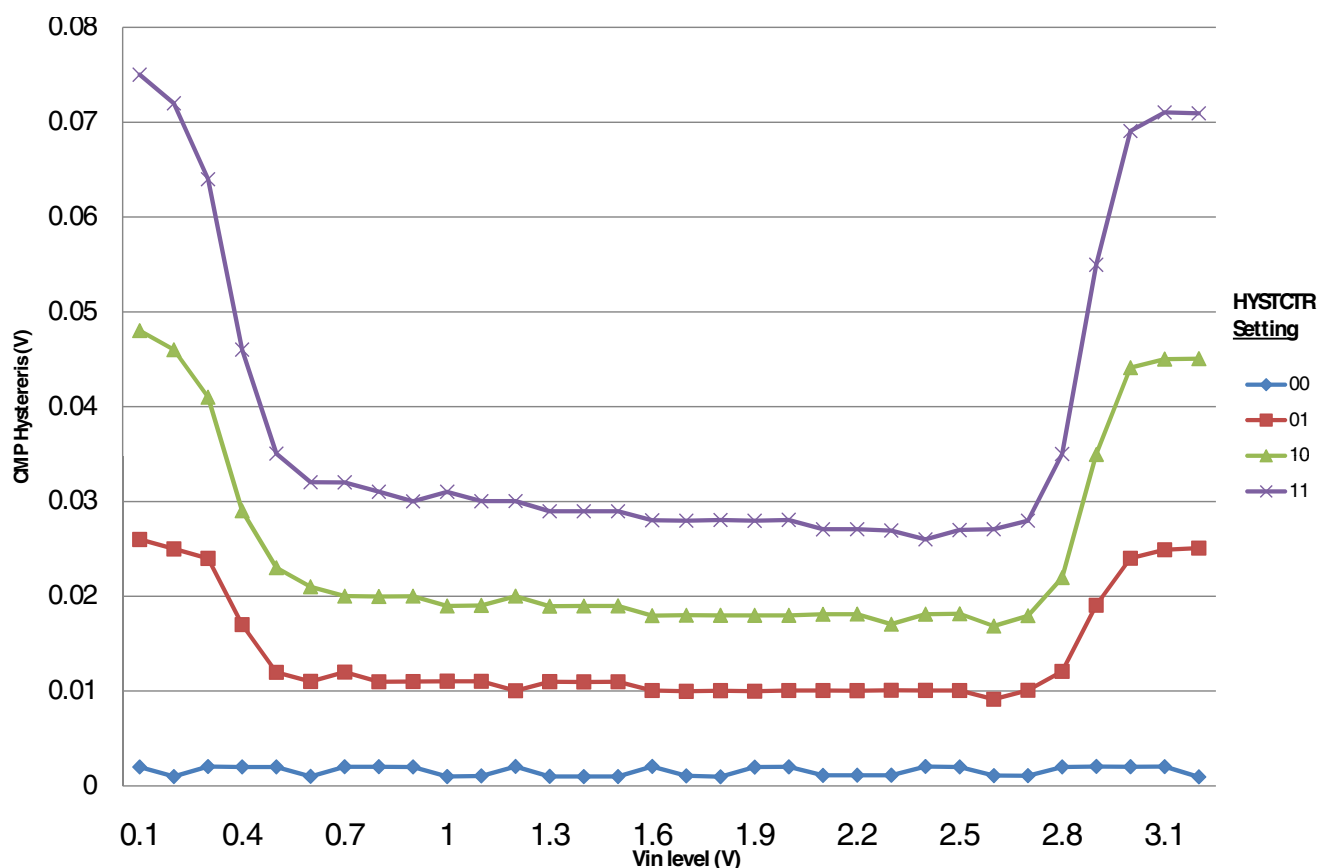

Figure 4. Typical hysteresis vs. Vin level (VDD = 3.3 V, PMODE = 0)

Table 31. VREF full-range operating behaviors (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
VREFH	Voltage reference output — user trim	1.178	—	1.202	V	
VREFL	Voltage reference output	0.38	0.4	0.42	V	
V _{step}	Voltage reference trim step	—	0.5	—	mV	
V _{tdrift}	Temperature drift (V _{max} - V _{min} across the full temperature range)	—	5	—	mV	1
A _c	Aging coefficient	—	—	400	uV/yr	
I _{bg}	Bandgap only current	—	—	80	μA	2
I _{lp}	Low-power buffer current	—	—	0.19	μA	2
I _{hp}	High-power buffer current	—	—	0.5	mA	2
I _{LOAD}	VREF buffer current	—	—	1	mA	3
ΔV _{LOAD}	Load regulation <ul style="list-style-type: none"> current = + 1.0 mA current = - 1.0 mA 	—	2 5	—	mV	2, 4
T _{stup}	Buffer startup time	—	—	20	ms	
V _{vdift}	Voltage drift (V _{max} - V _{min} across the full voltage range)	—	0.5	—	mV	2

1. For temp range -40 °C to 105 °C, this value is 15 mV
2. See the chip's Reference Manual for the appropriate settings of VREF Status and Control register.
3. See the chip's Reference Manual for the appropriate settings of SIM Miscellaneous Control Register.
4. Load regulation voltage is the difference between VREFH voltage with no load vs. voltage with defined load.

Table 32. VREF limited-range operating requirements

Symbol	Description	Min.	Max.	Unit	Notes
T _A	Temperature	0	50	°C	

Table 33. VREF limited-range operating behaviours

Symbol	Description	Min.	Max.	Unit	Notes
VREFH	Voltage reference output with factory trim	1.173	1.225	V	
VREFL	Voltage reference output	0.38	0.42	V	

6.4.4 AFE electrical specifications

6.4.4.2 $\Sigma\Delta$ ADC Standalone specifications

Table 35. $\Sigma\Delta$ ADC standalone specifications

Symbol	Description	Conditions	Min	Typ ¹	Max	Unit	Notes
f_{Nyq}	Input bandwidth	Normal Mode Low-Power Mode	1.5 1.5	1.5 1.5	1.5 1.5	kHz	
V_{CM}	Input Common Mode Reference		0		0.8	V	
V_{INdiff}	Input range	Differential		+/- 500		mV	
		Single Ended		+/- 250		mV	
SNR	Signal to Noise Ratio	Normal Mode <ul style="list-style-type: none"> $f_{IN}=50\text{Hz}$; common mode=0V, $V_{pp}=500\text{mV}$ (differential ended) $f_{IN}=50\text{Hz}$; common mode=0V, $V_{pp}=500\text{mV}$ (full range se.) Low-Power Mode <ul style="list-style-type: none"> $f_{IN}=50\text{Hz}$; common mode=0V, $V_{pp}=500\text{mV}$ (diff.) $f_{IN}=50\text{Hz}$; common mode=0V, $V_{pp}=500\text{mV}$ (full range se.) 	88 76	90 78		dB	
$\Delta\text{Gain}_{T_{E_{mp}}}$	Gain Temperate Drift - Gain error caused by temperature drifts ²	<ul style="list-style-type: none"> Gain bypassed $V_{pp} = 500\text{ mV}$ (differential) PGA bypassed $V_{pp} = 500\text{ mV}$ (differential), $V_{CM} = 0\text{ V}$ 			55	ppm/°C	
$\Delta\text{Offset}_{Temp}$	Offset Temperate Drift - Offset error caused by temperature drifts ³	<ul style="list-style-type: none"> Gain bypassed $V_{pp} = 500\text{ mV}$ (differential), $V_{CM} = 0\text{ V}$ 			30	ppm/°C	
SINAD	Signal-to-Noise + Distortion Ratio	Normal Mode <ul style="list-style-type: none"> $f_{IN}=50\text{Hz}$; common mode=0V, $V_{pp}=500\text{mV}$ (diff.) $f_{IN}=50\text{Hz}$; common mode=0V, $V_{pp}=500\text{mV}$ (full range se.) Low-Power Mode <ul style="list-style-type: none"> $f_{IN}=50\text{Hz}$; common mode=0V, $V_{pp}=500\text{mV}$ (diff.) $f_{IN}=50\text{Hz}$; common mode=0V, $V_{pp}=500\text{mV}$ (full range se.) 		80 74		dB	
CMMR	Common Mode Rejection Ratio	<ul style="list-style-type: none"> $f_{IN}=50\text{Hz}$; common mode=0V, $V_{id}=100\text{ mV}$ 		90		dB	
PSRR_{AC}	AC Power Supply Rejection Ratio	Gain=01, $V_{CC} = 3\text{V} \pm 100\text{mV}$, $f_{IN} = 50\text{ Hz}$		60		dB	
XT	Crosstalk	Gain=01, $V_{id} = 500\text{ mV}$, $f_{IN} = 50\text{ Hz}$			-100	dB	
f_{MCLK}	Modulator Clock Frequency Range	Normal Mode Low-Power Mode	0.03 0.03		6.5 1.6	MHz	
I_{DDA_ADC}	Current Consumption by ADC (each channel)	Normal Mode ($f_{MCLK} = 6.144\text{ MHz}$, $\text{OSR}=2048$) Low-Power Mode ($f_{MCLK} = 0.768\text{MHz}$, $\text{OSR}=256$)			1.4 0.5	mA	

Table 38. SPI switching characteristics at 1.7 V (1.7 - 3.6) (continued)

Description	Min.	Max.	Unit	Notes
Rise time input • Master • Slave	1 1		ns	
Fall time input • Master • Slave	1 1		ns	
Rise time output • Master • Slave	30.4 30.4		ns	
Fall time output • Master • Slave	33.5 29.0		ns	

Table 39. SPI switching characteristics at 2.7 V (2.7 - 3.6)

Description	Min.	Max.	Unit	Notes
Data Setup Time (inputs, tSUI) • Master • Slave	29 4		ns	
Input Data Hold Time (inputs, tHI) • Master • Slave	0 1		ns	
Data hold time (outputs, tHO) • Master • Slave	0 0		ns	
Data Valid Out Time (after SCK edge, tDVO) • Master • Slave	49 49		ns	
Rise time input • Master • Slave	1 1		ns	
Fall time input • Master • Slave	1 1		ns	
Rise time output • Master • Slave	17.3 17.3		ns	
Fall time output • Master • Slave	16.6 16.0		ns	

6.7 Human-Machine Interfaces (HMI)

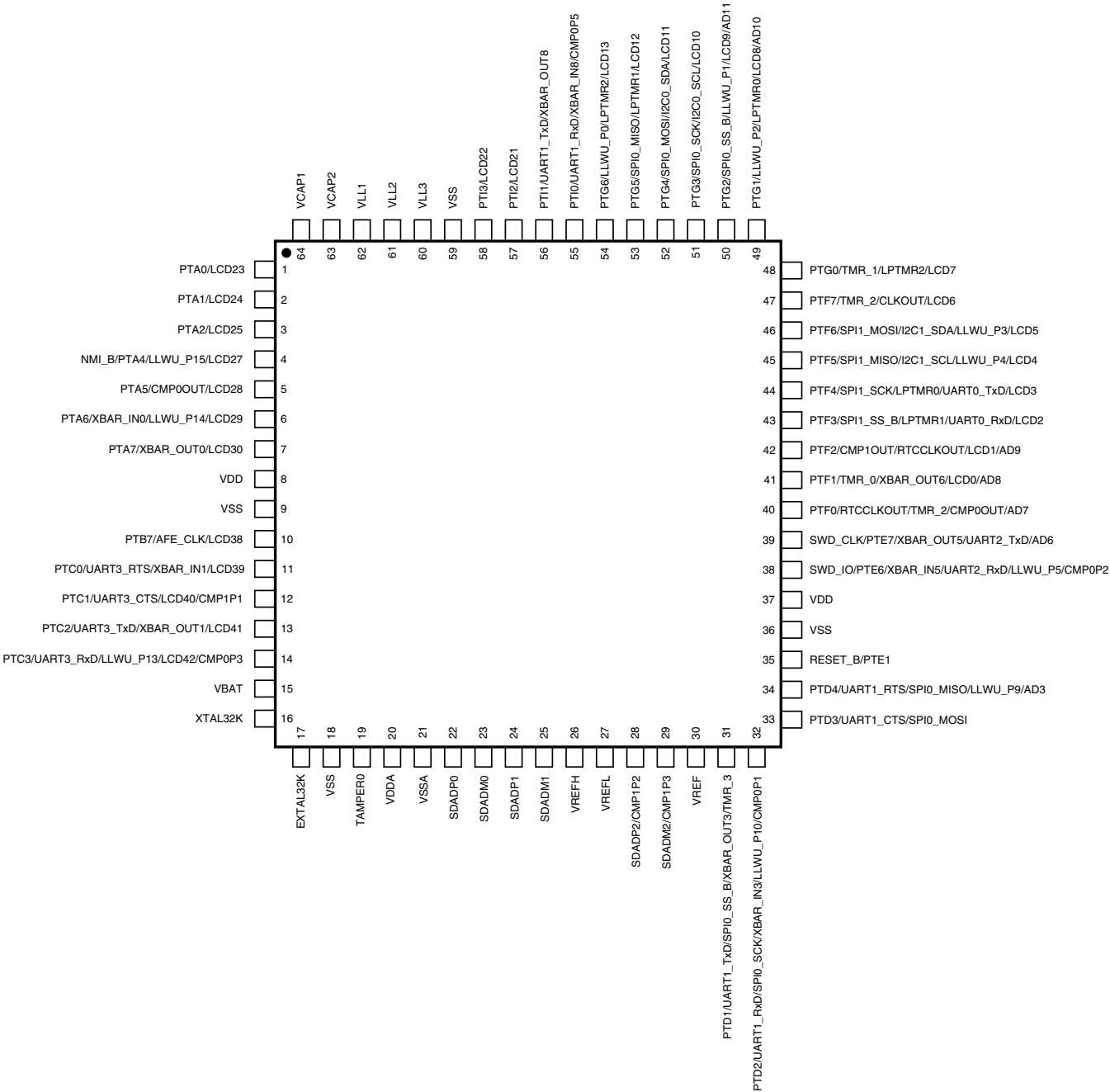


Figure 7. 64-pin LQFP Pinout Diagram

8.2.3 44-pin LGA

The following figure represents 44-pin LGA pinouts: